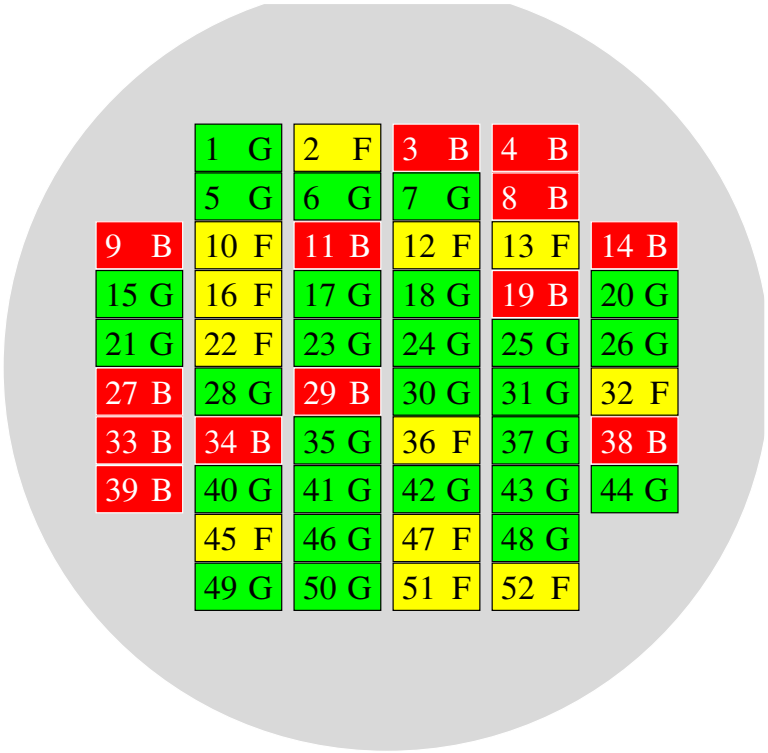
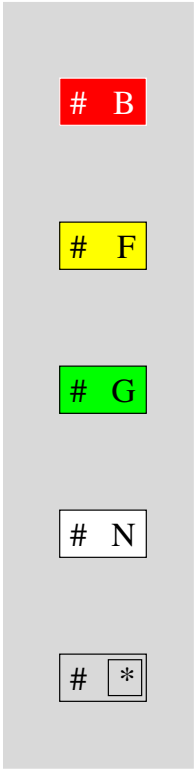
Die quality map for wafer 38 s/n: 21316-03-10

Date: 11/01/98